

WHAT IS CLAIMED IS:

- Sub B1*
1. Method of information collection and processing of sample's surface, including successive reading of at least a portion of force curve, in predetermined points of surface under control within the process of approach and/or move apart (which goes after reverse) of sample and probe, which is set up at cantilever, and determination (according to it) of sample's parameters with further construction of appropriate space distributions, which differs by, that choice of points of control is carried out and values of cantilever's deviation force are noted within reading of at least a portion of force curve, as well as: and/or coordinates of its fixed end are; and/or derivatives from cantilever's deviation force of coordinate of its fixed end are at least in points of control of force curve, upon that, parameters of sample, characterizing relief and/or properties of sample's surface and/or a number and properties of its surface layers are determined by a number of points of control, and/or noted values of cantilever's deviation force, and/or coordinates of its fixed end, and/or derivatives from cantilever's deviation force of coordinate of its fixed end in appropriate points of control.
2. Method, as set forth in claim 1, differing by, that coordinates of sample's surface and/or of limits of their surface layers, or thickness of surface layers, or adhesion force of sample's surface and/or surface layers, or elasticity coefficient of sample's surface and/or surface layers, or frictional force of sample's surface and/or surface layers are used in the character of parameters, characterizing relief and/or properties of sample's surface and/or a number and properties of its surface layers.
- Sub A1*
3. Method, as set forth in claims 1 and 2, differing by, that a set of arguments are formed by values of cantilever's deviation force and/or coordinate of its fixed end and/or derivatives from cantilever's deviation force of coordinate of its

Control
sub. 1 → fixed end at least in points of control; determination of parameters is carried out by the way of forming of a set of functions, using received arguments and determination of their values.

4. Method, as set forth in claims 1-3, differing by, that points, limiting quasi-rectilinear portions of force curve, and/or points, where force curve shifts slope jumpy, are chosen as points of control.

5. Method, as set forth in claims 1-3, differing by, that points, where coordinate of fixed end of cantilever and/or force of its deviation and/or its first or second derivatives according to coordinate of fixed cantilever's end, achieve threshold values, received, e.g., using results of previous scanning or measurement are chosen as points of control.

6. Method, as set forth in claims 1-5, differing by, that construction of space distributions is carried out concerning coordinate of sample's surface.

Sub B1
ant → 7. Method, as set forth in claim 1, differing by, that choosing of points of control and/or noting of values of cantilever's deviation force, and/or coordinates of its fixed end, and/or derivatives from cantilever's deviation force of coordinate of its fixed end, are carried out after filtration of a set of current values of cantilever's deviation force and coordinates of its fixed end.

Sub. 2 → 8. Method, as set forth in claims 1-3, differing by, that determination of parameters, using noted values of cantilever's deviation force and/or coordinates of its fixed end and/or derivatives from cantilever's deviation force of coordinate of its fixed end in a predetermined subset of points of control is carried out, taking into consideration values of indicated magnitudes in other subsets of points of control.

00000000000000000000000000000000

9. Method, as set forth in claim 1, differing by, that determination of parameters is carried out according to noted values of cantilever's deviation force and/or coordinate of its fixed end and/or derivatives from cantilever's deviation force according to coordinate of its fixed end in points of control, placed before and after or after and before absolute maximum of cantilever's deviation force within the process of approach and sample's move apart accordingly.

10. Method, as set forth in claim 2, differing by, that a number of surface layers of sample is determined as a number of points of control, limiting quasi-rectilinear portions of force curve; and/or as a number of points, where force curve shifts slope jumpy without unit and reverse point within the process of approach and move apart of sample and probe, if it is included into a number of points of control.

11. Method, as set forth in claim 10, differing by, that initial points of quasi-vertical portions are not taken into account upon determination of a number of surface layers of sample.

12. Method, as set forth in claim 2, differing by, that coordinate of sample's surface is determined by relationship:

$$R_0 = Z_0 - S_0$$

where R_0 is coordinate of sample's surface,

Zo, So is coordinate of fixed cantilever's end and magnitude of deviation of its free end at the moment of achievement (by cantilever's deviation force) of a value, equal to 0 or $-A$ within approach of sample and probe, and 0 or $+A$ within move apart of sample and probe, accordingly,

A is positive constant magnitude.

14. Method, as set forth in claim 2, differing by, that coordinates of limits of surface layers of sample are determined as coordinates of fixed cantilever's end in points of control, not including initial points of quasi-vertical portions within approach of sample and probe and final points of quasi-vertical portions within move apart of sample and probe.

$R_i = Z_i - S_i$, $D_i = [R(i+1) - R_i]$, where R_i and D_i are coordinate of limit of i -layer and its thickness accordingly, $i = (0, 1, 2...)$,

Z_i , S_i are coordinate of cantilever's fixed end and magnitude of deviation of its free end in an appropriate point of control, not including initial points of quasi-vertical points within approach of sample and probe, and final points of quasi-vertical portions within move apart of probe and sample.

16. Method, as set forth in claim 2, differing by, that coordinates of limits of surface layers of sample relatively sample's surface and their thicknesses are determined according to relationships like:

$R'_i = Z_i - S_i - R_0$, $D_i = [R'_{i+1} - R'_i]$, where R'_i and D_i is coordinate of limit of i -layer, concerning sample's surface and its thickness accordingly, $i = (0, 1, 2...)$,

Z_i , S_i are coordinate of cantilever's fixed end and magnitude of deviation of its free end accordingly in an appropriate point of control, not including initial

points of quasi-vertical portions within approach of sample and probe and final points of quasi-vertical portions within move apart of sample and probe.

17. Method, as set forth in claims 14-16, differing by, that coordinates of limits of surface layers of sample (measured within approach or move apart), are determined relatively coordinate of surface, which is measured also within move apart or approach accordingly.

18. Method, as set forth in claim 2, differing by, that adhesion force of surface layers of sample is determined by values of cantilever's deviation force in points of control, not including final points of quasi-vertical portions within move apart of sample and probe.

19. Method, as set forth in claim 2, differing by, that summary adhesion force of surface and surface layers of sample is determined as an absolute maximum of cantilever's deviation force within the process of move apart of probe and sample.

20. Method, as set forth in claim 2, differing by, that coordinate of sample's surface is determined with a correction for summary adhesion force, which takes place between probe and surface, according to relationship:

$R_{oa} = R_o + F_{ac}/K_p$, where R_{oa} is coordinate of sample's surface with a correction taking into account summary adhesion force, which takes place between probe and surface,

F_{ac} is summary adhesion force of sample's surface,

$K_p = K_k * \tan \alpha / (1 - \tan \alpha)$,

K_k is coefficient of cantilever's elasticity for bending,

$\tan \alpha$ is slope of force curve in the vicinity of point Z_o .

21. Method, as set forth in claim 2, differing by, that coordinate of sample's surface is determined with a correction taking into account elastic properties of surface, according to relationship:

$$R_{\text{oy}} = R_{\text{o}} + S_{\text{o}}(K_{\text{k}}/K_{\text{p}}) \text{ upon } R_{\text{o}} = Z_{\text{o}} - S_{\text{o}},$$

$$\text{Roy} = Z_t - S_t + S_t(K_k/K_p) \text{ upon } Z_t - S_t = \text{constant},$$

where Roy is surface coordinate.

22. Method, as set forth in claim 2, differing by, that coefficient of elasticity of surface layers of sample is determined according to relationship:

$$K_i = B^* K_k^* \operatorname{tg} \alpha_i / (1 - \operatorname{tg} \alpha_i),$$

where K_i is coefficient of elasticity of i -layer;

$\tan \alpha$ is slope of a portion of force curve, placed between appropriate points of control, B is coefficient of proportionality.

23. Method, as set forth in claim 2, differing by, that coefficient of elasticity of sample's surface is determined according to relationship:

$$K_p = K_k^* \operatorname{tg} \alpha / (1 - \operatorname{tg} \alpha),$$

where K_p is coefficient of elasticity of sample's surface.

24. Method, as set forth in claim 2, differing by, that approach and/or move apart of sample and probe are carried out before achievement of threshold value by cantilever's deviation force.

25. Method, as set forth in claim 1, differing by, that reading of force curve is carried out more than one time in predetermined points of sample's surface under control.

Sh
Bl
ant

1979 1978 1977 1976 1975 1974 1973 1972 1971 1970 1969 1968 1967 1966 1965 1964 1963 1962 1961 1960 1959 1958 1957 1956 1955 1954 1953 1952 1951 1950 1949 1948 1947 1946 1945 1944 1943 1942 1941 1940 1939 1938 1937 1936 1935 1934 1933 1932 1931 1930 1929 1928 1927 1926 1925 1924 1923 1922 1921 1920 1919 1918 1917 1916 1915 1914 1913 1912 1911 1910 1909 1908 1907 1906 1905 1904 1903 1902 1901 1900 1899 1898 1897 1896 1895 1894 1893 1892 1891 1890 1889 1888 1887 1886 1885 1884 1883 1882 1881 1880 1879 1878 1877 1876 1875 1874 1873 1872 1871 1870 1869 1868 1867 1866 1865 1864 1863 1862 1861 1860 1859 1858 1857 1856 1855 1854 1853 1852 1851 1850 1849 1848 1847 1846 1845 1844 1843 1842 1841 1840 1839 1838 1837 1836 1835 1834 1833 1832 1831 1830 1829 1828 1827 1826 1825 1824 1823 1822 1821 1820 1819 1818 1817 1816 1815 1814 1813 1812 1811 1810 1809 1808 1807 1806 1805 1804 1803 1802 1801 1800 1799 1798 1797 1796 1795 1794 1793 1792 1791 1790 1789 1788 1787 1786 1785 1784 1783 1782 1781 1780 1779 1778 1777 1776 1775 1774 1773 1772 1771 1770 1769 1768 1767 1766 1765 1764 1763 1762 1761 1760 1759 1758 1757 1756 1755 1754 1753 1752 1751 1750 1749 1748 1747 1746 1745 1744 1743 1742 1741 1740 1739 1738 1737 1736 1735 1734 1733 1732 1731 1730 1729 1728 1727 1726 1725 1724 1723 1722 1721 1720 1719 1718 1717 1716 1715 1714 1713 1712 1711 1710 1709 1708 1707 1706 1705 1704 1703 1702 1701 1700 1699 1698 1697 1696 1695 1694 1693 1692 1691 1690 1689 1688 1687 1686 1685 1684 1683 1682 1681 1680 1679 1678 1677 1676 1675 1674 1673 1672 1671 1670 1669 1668 1667 1666 1665 1664 1663 1662 1661 1660 1659 1658 1657 1656 1655 1654 1653 1652 1651 1650 1649 1648 1647 1646 1645 1644 1643 1642 1641 1640 1639 1638 1637 1636 1635 1634 1633 1632 1631 1630 1629 1628 1627 1626 1625 1624 1623 1622 1621 1620 1619 1618 1617 1616 1615 1614 1613 1612 1611 1610 1609 1608 1607 1606 1605 1604 1603 1602 1601 1600 1599 1598 1597 1596 1595 1594 1593 1592 1591 1590 1589 1588 1587 1586 1585 1584 1583 1582 1581 1580 1579 1578 1577 1576 1575 1574 1573 1572 1571 1570 1569 1568 1567 1566 1565 1564 1563 1562 1561 1560 1559 1558 1557 1556 1555 1554 1553 1552 1551 1550 1549 1548 1547 1546 1545 1544 1543 1542 1541 1540 1539 1538 1537 1536 1535 1534 1533 1532 1531 1530 1529 1528 1527 1526 1525 1524 1523 1522 1521 1520 1519 1518 1517 1516 1515 1514 1513 1512 1511 1510 1509 1508 1507 1506 1505 1504 1503 1502 1501 1500 1499 1498 1497 1496 1495 1494 1493 1492 1491 1490 1489 1488 1487 1486 1485 1484 1483 1482 1481 1480 1479 1478 1477 1476 1475 1474 1473 1472 1471 1470 1469 1468 1467 1466 1465 1464 1463 1462 1461 1460 1459 1458 1457 1456 1455 1454 1453 1452 1451 1450 1449 1448 1447 1446 1445 1444 1443 1442 1441 1440 1439 1438 1437 1436 1435 1434 1433 1432 1431 1430 1429 1428 1427 1426 1425 1424 1423 1422 1421 1420 1419 1418 1417 1416 1415 1414 1413 1412 1411 1410 1409 1408 1407 1406 1405 1404 1403 1402 1401 1400 1399 1398 1397 1396 1395 1394 1393 1392 1391 1390 1389 1388 1387 1386 1385 1384 1383 1382 1381 1380 1379 1378 1377 1376 1375 1374 1373 1372 1371 1370 1369 1368 1367 1366 1365 1364 1363 1362 1361 1360 1359 1358 1357 1356 1355 1354 1353 1352 1351 1350 1349 1348 1347 1346 1345 1344 1343 1342 1341 1340 1339 1338 1337 1336 1335 1334 1333 1332 1331 1330 1329 1328 1327 1326 1325 1324 1323 1322 1321 1320 1319 1318 1317 1316 1315 1314 1313 1312 1311 1310 1309 1308 1307 1306 1305 1304 1303 1302 1301 1300 1299 1298 1297 1296 1295 1294 1293 1292 1291 1290 1289 1288 1287 1286 1285 1284 1283 1282 1281 1280 1279 1278 1277 1276 1275 1274 1273 1272 1271 1270 1269 1268 1267 1266 1265 1264 1263 1262 1261 1260 1259 1258 1257 1256 1255 1254 1253 1252 1251 1250 1249 1248 1247 1246 1245 1244 1243 1242 1241 1240 1239 1238 1237 1236 1235 1234 1233 1232 1231 1230 1229 1228 1227 1226 1225 1224 1223 1222 1221 1220 1219 1218 1217 1216 1215 1214 1213 1212 1211 1210 1209 1208 1207 1206 1205 1204 1203 1202 1201 1200 1199 1198 1197 1196 1195 1194 1193 1192 1191 1190 1189 1188 1187 1186 1185 1184 1183 1182 1181 1180 1179 1178 1177 1176 1175 1174 1173 1172 1171 1170 1169 1168 1167 1166 1165 1164 1163 1162 1161

Sch
B
Curt

[illegible]

28. Method, as set forth in claim 1, differing by, that reading of force curve control is carried out more than one time in predetermined points of sample's surface under control, upon different electric potential of probe relatively sample's surface, determining magnitude of electric interaction force of probe and sample and/or surface layers of sample, using difference of received values of cantilever's deviation force.

29. Method, as set forth in claim 1, differing by, that reading of force curve control is carried out more than one time in predetermined points of sample's surface under control, upon different electric potential of probe relatively sample's surface, determining magnitude of gradient of electric interaction force of probe and surface and/or surface layers of sample, using difference of received values of derivatives of cantilever's deviation force, according to coordinate of fixed end.

30. Method, as set forth in claim 1, differing by, that registration of magnitude of tunnel current between conducting probe and sample's surface is carried out together with reading of force curve or of its portion, using received set of

Sun
B
ant

0000000000